


<b>Search Notes</b> 	Application No.		Applicant(s)	
	10/784,291		HU ET AL.	
	Examiner		Art Unit	
	Philip H Leung		3742	

SEARCHED			
Class	Subclass	Date	Examiner
219	741-744	6/25/2004	re P.L.
174	35R, 35GC		
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updated 1/4/05 re			
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updated 3/23/05 re			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
as above		3/23/05	re

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Searched Inventorship checked	6/25/2004	re P.L.

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